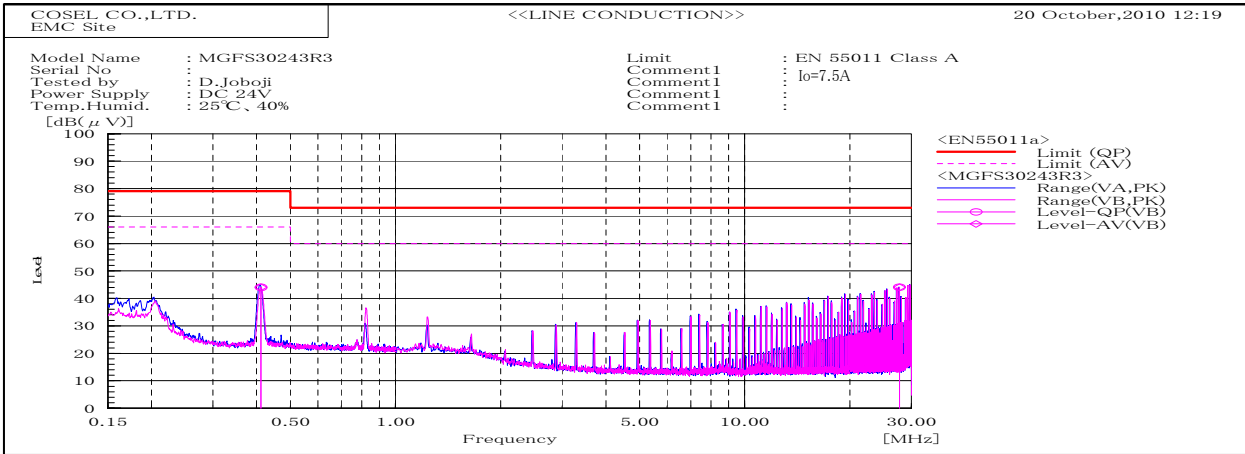
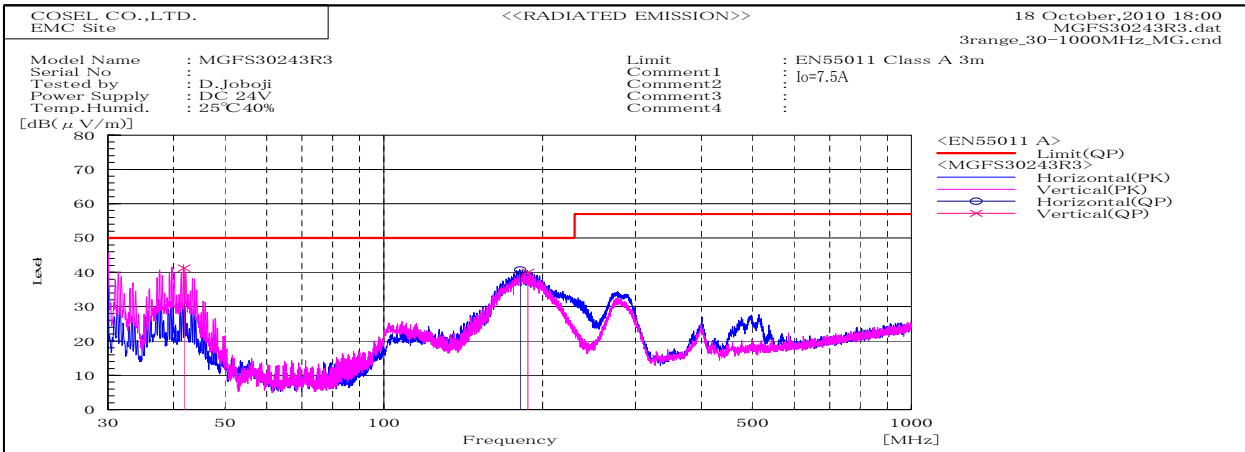


<b>DATA SHEET</b>		Date	20-Oct-10
Model	MGFS30243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.41203		VB	34	34.1	10	44	44.1	79	66	35	21.9	Pass	
27.7314		VB	33.1	33.1	11	44.1	44.1	73	60	28.9	15.9	Pass	

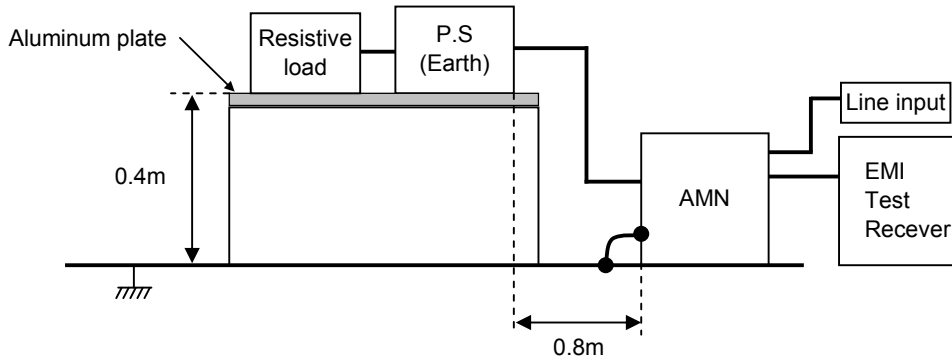


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP			QP	QP						
41.826	V	Stable	60.7	-19.5		41.2		50	8.8	Pass	102	83	
181.474	H	Stable	62.9	-22.2		40.7		50	9.3	Pass	155	181	
187.759	V	Stable	62.1	-22.1		40		50	10	Pass	108	65	

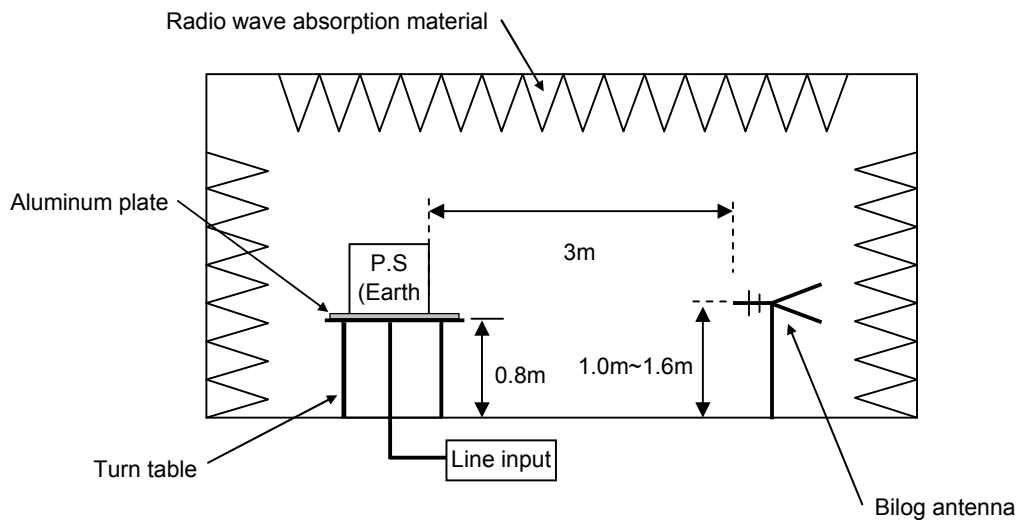
**DATA SHEET**

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

**1. Line conduction**



**2. Radiated emission**



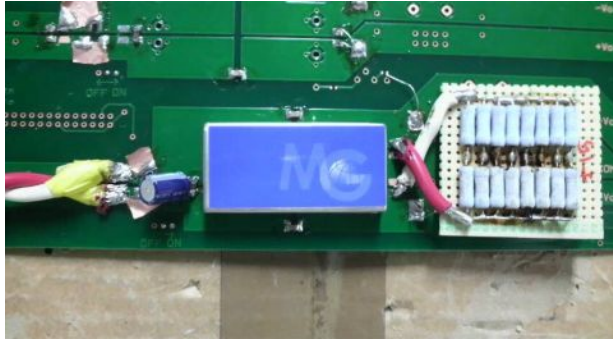


Conditions

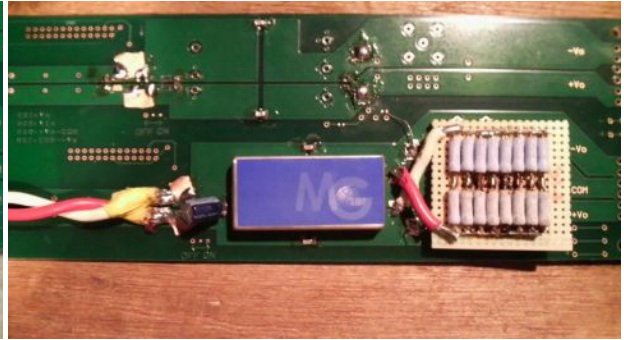
Test : EMI  
 Model Name : MGFS3024□□/MGFW3024□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

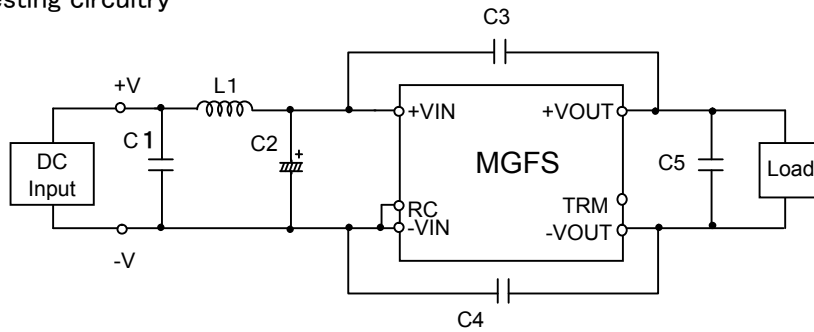


Fig.1 Testing circuitry 1

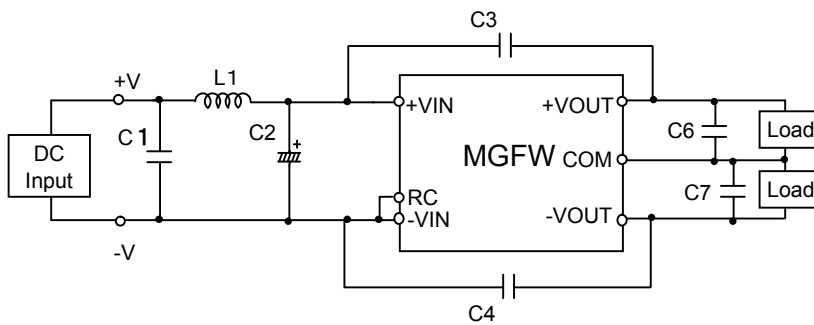


Fig.2 Testing circuitry 2

L1	: 0.6uH	CI8C-0R6	(KORIN ELECTRONICS)
C1	: 50V	4.7 μ F	Ceramic Capacitor
C2	: 50V	100 μ F	Electrolytic Capacitor
C3,C4	: 2kV	1000pF	Ceramic Capacitor
C5,C6,C7	: 25V	22 μ F	Ceramic Capacitor